

**Search Notes**

Application/Control No.

10/537,372

Examiner

CHRIS C. CHU

Applicant(s)/Patent under  
Reexamination

DIEM ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	E21.32, 678, 701, 414 & 415	6/22/2008	C.C.
257	417 & 704	6/22/2008	C.C.
257	710 & 723	6/22/2008	C.C.
438	106 & 121	6/22/2008	C.C.
438	125 & 456	6/22/2008	C.C.
438	723	6/22/2008	C.C.
216	2 & 79	6/22/2008	C.C.
73	504.12	6/22/2008	C.C.
73	504.02	6/22/2008	C.C.
73	504.14	6/22/2008	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
<b>As same</b>	<b>as above</b>	6/22/2008	<b>C.C.</b>

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	6/22/2008	C.C.